


<b>Search Notes</b>  	<b>Application/Control No.</b>  10050133	<b>Applicant(s)/Patent Under Reexamination</b>  NARUSAWA, HIDEKI
	<b>Examiner</b>  Gauthier, Gerald	<b>Art Unit</b>  2614

SEARCHED			
Class	Subclass	Date	Examiner
379	93.17	12/21/2006	GG
455	66.1, 410, 437, 550.1, 551	12/21/2006	GG
340	7.52	12/21/2006	GG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	7/20/2006	GG
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	12/21/2006	GG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner